

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Hiroe KAWAMURA

Serial Number: Not Yet Assigned

Filed: February 23, 2004

Customer No.: 38834

For: MANUFACTURING METHOD OF SEMICONDUCTOR DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

February 23, 2004

Sir:

In compliance with 37 CFR 1.56, Applicant(s) call(s) to the attention of the Patent and Trademark Office the references listed on the attached PTO-1449.

A copy of each of the references is enclosed herewith.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,
WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP



John P. Kong
Reg.: 40,054

Atty. Docket No.: 042138
1250 Connecticut Avenue, N.W., Suite 700
Washington, D.C. 20036
Tele: (202) 822-1100
Fax: (202) 822-1111
JPK/ll
Enclosures: PTO-1449; References (12)

INFORMATION DISCLOSURE STATEMENT PTO-1449	Atty. Docket No.: 042138	Serial No.: 10/380,468
	Applicants: Hiroe KAWAMURA	
	Filing Date: February 23, 2004	Group Art Unit: 3644

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
_____	AA					
_____	AB					

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)
_____	AC 09-051097 ~	02/18/97	Japan	Abstract & Discussed in the Spec.
_____	AD 2002-091342 ~	03/27/02	Japan	Abstract & Discussed in the Spec.
_____	AE 10-326790 ~	12/08/98	Japan	Abstract & Discussed in the Spec.
_____	AF 10-335659 ~	12/18/98	Japan	Abstract & Discussed in the Spec.
_____	AG 08-264780 ~	10/11/96	Japan	Abstract & Discussed in the Spec.
_____	AH 08-264401 ~	10/11/96	Japan	Abstract & Discussed in the Spec.
_____	AI 08-264402 ~	10/11/96	Japan	Abstract & Discussed in the Spec.
_____	AJ 08-321443 ~	12/03/96	Japan	Abstract & Discussed in the Spec.
_____	AK 05-347256 ~	12/27/93	Japan	Abstract & Discussed in the Spec.
_____	AL 2002-003295 ~	01/09/02	Japan	Abstract & Discussed in the Spec.
_____	AM			

OTHER DOCUMENTS

_____	AN	H. Sayama et al., "Effect of <100> Channel Direction for High Performance SCE Immune pMOSFET with Less Than 0.15μm Gate Length", IEEE, 1999
_____	AO	
Examiner		Date Considered